


Search Notes 	Application/Control No. 10776789	Applicant(s)/Patent Under Reexamination BEDNASZ ET AL.
	Examiner Pan, Yuwen	Art Unit 2618

SEARCHED			
Class	Subclass	Date	Examiner
455	67.11, 67.14	1/16/08	YP
343	703, 702	1/16/08	YP

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search	1/16/08	YP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
455	67.14	10/15/08	YP

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